

Search Notes

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Examiner

Hai L. Nguyen

Applicant(s)/Patent under
Reexamination

DUPUY ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	50-54,62, 63,65-67, 103	2/14/2005	HLN
327	318,319	2/14/2005	HLN
HLN	333	2/14/2005	HLN
326	62,63	2/14/2005	HLN
326	80,81	2/14/2005	HLN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Search	Above	2/14/2005	HLN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	2/14/2005	HLN